Agilent Logic Analyzer Cheat Sheet

Connect What is the best way to probe the target signals, given their unique characteristics? **Probing:** Ensure the probe connection to the DUT supports the characteristics of the State & Timing Speeds: Select a logic analyzer with a max state speed at least as high as the bus data rate and signals being probed (probe bandwidth to match the signal speeds, impact of probe max timing rate at least 4 to 10 times the bus data rate. loading on the target device and measurement accuracy, signal type – single-ended or differential, minimum signal amplitude, etc.). Also – will the customer be designing in probing connections or connecting to individual signals after the design is complete? Connection to the DUT can also be by done via analysis probe, interposer, etc.

NOTE: Probes are ordered separately. Specify probes when ordering to ensure the correct connection between the logic analyzer and device under test. Recommend ordering enough probes for the number of channels selected unless other probing options are available (analysis probe, interposer, etc.)

Considerations When Configuring a Logic Analyzer (App note: http://cp.literature.agilent.com/litweb/pdf/5989-5138EN.pdf) Acquire

What is the right combination of acquisition capabilities required to address the measurement needs?

Channels: Each channel represents one signal. Select a system with enough channels for the application. Recommend getting additional channels to look at other buses or for future needs. NOTE: Channel count is not upgradeable in portable configurations – order enough channels for future needs.

Memory Depth: Due to the complexity of today's digital buses, the logic analyzer must have enough acquisition memory to capture as much system activity as possible. For tight budgets, purchase the amount of memory needed for now and upgrade as needs evolve. NOTE: if all channels are used, memory depth is halved in state mode.

What is the most efficient way to analyze the captured data? Application and Analysis Tools: Agilent and our partners provide an extensive range of FPGA, processor, bus and analysis tools. Analysis tools help rapidly consolidate data into displays that provide insight into the system's behavior – saving the customer time.

View and Analyze

NOTE: Use the logic analyzer configuration spreadsheet to determine if application support is available for the specific application, as well as logic analyzer compatibility. Agilent and its 3rd parties are available to develop custom solutions also.

						Logic Analyzer Portfolio	http://www.agil	ent.com/find/logic				
Product Family		16800 Series Portable Logic Analyzers				1690	00 Series Modular	AXIe-based Lo	ogic Analyzers			
Vebsites and		www.agieInt.com/find/16800					www.agilent.o	com/find/16900		www.agilent.com/find/U4154A		
Oata Sheets	Benefits of a 16800 Series portable logic analyzer Delivers an exclusive combination of logic analysis, pattern generation, application software, and innovative probing – all at a price to fit limited budgets. Built in 48-ch pattern generator available on select models Bundels support a wide range of applications (34, 68, 102, 136, or 204 channels) Affordable fixed configurations Features					Mainframes: htt	tp://cp.literture.ag	Chassis: http://cp.literature.agilent.com/litweb/pdf/5990-6584EN				
						Measurement Module	es: http://cp.litert	U4154A: http://cp.literature.agilent.com/litweb/pdf/5990-7513EN				
						Benefits of a 16900 Series modular system		Benefits of an AXIe-based logic analyzer AXIe-based modular platform supported multiple buses including logic analyzer				
						Flexibility to configure the system for specific and a specif	•					
						Long-term investment protection – upgrade o	_	HDMI & MHL Protocol Analyzer and Generator Module, PCIE Gen 3 analy.				
						Maximize measurement capability: highest channel counts, highest state (2 GHz) and timing (8 GHz) speeds, deepest memory depth (up to 256 M), single ended and differential signal support				 module, and etc. AXIe chassis provide a high-performance platform to compliment PXI-base 		
						256 M), single ended and differential signal su	apport	systems				
										Long-term investment protection – upgrade or re-configure as needs evolved.		
										approve of the configure as fields evo		
									ferences relative to 16901A	U4154A features		
15" display, Touch screen optional (option 103)							e	State capture up to 4 Gb/s on 68 channels, 2.5 Gb/s on 136 channels per module The state capture up to 4 Gb/s on 68 channels, 2.5 Gb/s on 136 channels per module				
Logic analyzer cables egress from the side			asurement modules									
	External removable hard drive (option 109) See details below							cables egress from the rear	Trigger Sequence Rate, 2.5GHz			
						 External removable hard drive (option 109) Same footprint as 16800 series portable logic analyzer Built-in remova Largest footprin 			vable hard drive (standard)	12.5 GHz Timing Zoom with 256 K sample memory Reliable data capture on over appoints as small as 100 ps by 100 mV.		
	16800 Series Portable Logic Analyzers					16900 Series Logic Analyzer Largest rootpr				Reliable data capture on eye openings as small as 100 ps by 100 mV U4154A Logic Analyzer Module		
Model	16801A	16802A	16803A	16804A	16806A	16910A/16911A		50B/16951B	16962A	U4154A-01G	U4154A-02G	
ioue:	16821A	16822A	16823A	1000-17	10000A	(Entry Class)		Mid Range)	(High End)	(High End)	(Ultra High End)	
ogic Analyzer Channels	34	68	102	136	204	102 / 68	(1.	68	68		36	
attern Generator Channels	48	48	48	N/A	N/A	Requires 16720A module	Requires	16720A module	Requires 16720A module	N/A		
Max channels on single time base	34	68	68 102 136 204		340 / 510			340	272			
Number of analyzers (time bases)	1			2	•	2		2	1		1	
Maximum state clock rate	250 MHz	50 MHz 250 MHz (standard) 450 MHz with opt 500				250 MHz (standard) 667 MHz 450 MHz with opt 500		2 GHz	1.4 GHz	2.5 GHz		
Max state data rate	250 Mb/s) Mb/s 250 Mb/s (standard)				250 Mb/s (standard)	667 Mb/s (DDR)		2 Gb/s (DDR)	1.4 Gb/s (136 channels)	2.5 Gb/s (136 channels)	
	500 Mb/s with opt 500				500 Mb/s with opt 500	1066 Mb/s (Dual Sample)		2.5 Gb/s (Dual Sample)	2.8 Gb/s (68 channels)	4 Gb/s (68 channels)		
linimum state clock rate	Low Hz			Low Hz	Low Hz		40 MHz	12.5 MHz (single edge), 6.25 MHz (both edges)				
igh Speed Timing Zoom	4 GHz (250 ps) with 64k depth			4 GHz (250 ps) with 64k depth	4 GHz (250 ps) with 64k depth		N/A	12.5 GHz (80ps) with 256K depth				
Max timing sample rate	500 MHz half ch / 1 GHz full ch					500 MHz half ch / 1 GHz full ch	600 MHz half ch / 1.2 GHz full ch		8 GHz quarter ch / 4 GHz half ch /	5 GHz half ch / 2.5 GHz full ch		
qtr/half/full ch)									2 GHz full ch			
Fransitional timing	500 MHz (full ch)				500 MHz (full ch) 600 MHz (full ch)		8 GHz quarter ch / 4 GHz half ch /	5 GHz half ch / 2.5 GHz full ch				
									2 GHz full ch			
Memory depth	1 M standard					256 K standard 16950B: 1 M stnd, 4 M, 16 M, 32				2 M standard		
	4 M, 16 M, 32 M optional					1 M, 4 M, 16 M, 32 M optional			, , , ,	4 M, 8 M, 16 M, 32 M, 64 M, 128 M, 200 M optional		
upported signal types	Single-ended					Single-ended Single-ended and Differentia			Single-ended and Differential	Single-ended and Differential		
robe compatibility	40-pin cable connector					40-pin cable connector 90-pin cable connector			90-pin cable connector	90-pin cable connector		
	Patt	tern Generato	(,	16822A, and	16823A portable logic analyzers; 16720A modu		s systems)			etween -01G and -02G	
attern Generator Configuration	Half Channel					Full Channel			Max trigger sequencer rate	1.4 GHz	2.5 GHz	
laximum Clock	300 MHz					180 MHz			Minimum eye size	160 ps x 160 mV	100 ps x 100 mV	
ata Channels	24					48			Sample position adjustment resolution	20 ps	5 ps	
lemory depth in vectors	16 M					8 M			Threshold resolution	20 mV 2 mV		
ogic levels supported						.8 V, 3-state 2.5 V, 3-state 3.3 V, ECL, 5 V PECL, 3.3 V LVPECL, LVDS					1A-02G	
Data/Clock Pod Quantities	Must order at least one clock pod per pattern generator and at least one data pod for every 8 output channels. (Software license upgrade to 02G without any penal								02G without any penalty cost)			

Flying Lead Measure individual signals physically far apart or where a probe connector has not been designed in. A wide variety of accessories provide the flexibility to connect to IC pins, traces, vias, and any signal that resides on the surface of the board. E5383A: 17-ch (SE)	Mictor This reliable and cost- effective connector solution supports data rates up to 600 Mb/s. The probe requires a 38- pin connector designed into the target system. E5346A: 34-ch (SE)	This high-performance connector solution supports data rates up to 1.5 Gb/s. The probe requires a 100-pin Samtec connector designed into the target system.	Soft Touch Connectorless Reduce cost and shorten the design cycle by eliminating probing connectors. The proprietary micro spring-pin technology provides reliable contact to signal pads even when probing uneven or contaminated circuit board surfaces. E5404A: 34-ch (SE, Pro Series)	DDR2/3 BGA Probes The W2630A and W3630A Series of BGA probes traffic on industry standard DDR2/3 DIMMs with analyzer or 9000/90000 Series oscilloscope. The intrusive, electrical and mechanical connection DRAM.	n a 16900 Series logic probes provide a non-	ZIF Probes ZIF probes provi	de a connection between 90-pin logic analyzer vings of a compatible BGA probe.
Measure individual signals physically far apart or where a probe connector has not been designed in. A wide variety of accessories provide the flexibility to connect to IC pins, traces, vias, and any signal that resides on the surface of the board. E5383A: 17-ch (SE)	This reliable and cost- effective connector solution supports data rates up to 600 Mb/s. The probe requires a 38- pin connector designed into the target system.	This high-performance connector solution supports data rates up to 1.5 Gb/s. The probe requires a 100-pin Samtec connector designed into the target system.	Reduce cost and shorten the design cycle by eliminating probing connectors. The proprietary micro spring-pin technology provides reliable contact to signal pads even when probing uneven or contaminated circuit board surfaces.	The W2630A and W3630A Series of BGA probes traffic on industry standard DDR2/3 DIMMs with analyzer or 9000/90000 Series oscilloscope. The intrusive, electrical and mechanical connection	n a 16900 Series logic probes provide a non-	ZIF probes provi	
E5383A: 17-ch (SE)	E5346A: 34-ch (SE)	E5385A: 34-ch (SE)	EE404A: 24 ch (SE Dro Sorios)				
F5382A· 17-ch (SF)			E5394A: 34-ch (SE, Classic) E5396A: 17-ch (SE, Half-size Classic)	N/A		N/A	
E5381A: 17-ch (DF)	E5380A: 34-ch (SE)	E5378A: 34-ch (SE) E5379A: 17-ch (DF)	E5406A: 34-ch (SE, Pro Series) E5402A: 34-ch (SE, low profile, Pro Series) E5405A: 17-ch (DF, Pro Series) E5390A: 34-ch (SE, Classic) E5398A: 17-ch (SE, half-size Classic) E5387A: 17-ch (DF, Classic)	DDR2 BGA Probes W2631A: 42 signals + 3 diff clocks* (UDQS, LDQS, CK) W2632A: 16 signals + 1 diff clock (LDQS) W2633A: 32 signals + 2 diff clocks (LDQS, CK) W2634A: 8 signals + 1 diff clock (LDQS) *UDQS/UDQS# are available on the oscilloscope probing pads on the rigid flex but do not go to the logic analyzer cable.		ZIF Probe: Access (for DDR 2 BGA probes) E5384A: All x8 or x16 DRAM data buses E5326A: x16 DRAM data buses E5327A: two x8 DRAM data buses	
				DDR3 BGA Probes W3631A: DDR3 x16 command and data W3633A: DDR3 x4/x8 command and data (options specify quantity: 001 = qty 1, 002 = qty 2, 004 = qty 4)		ZIF Probes: Access (for DDR 3 BGA probes) E5845A: for X16 DRAM E5847A: for x8 DRAM	
Logic Analyzer Applicati	on Solutions (http://www.	agilent.com/find/logic-sw-app	os)		Related DDS Applicatio	n Solutions	
licated to debug. Internal probe	points can be moved is seco	onds B4656A FPGA	http://www.agilent.com/find/pcie			http://www.agilent.com/find/hdmi http://www.agilent.com/find/MHL HDMI / MHL	
v.agilent.com/find/fpga				Agilent's U4300 Digital Test Console PCI Express protocol test solution supports all	The Mobile Industry Processor Interface (MIPI) Alliance has defined standard interfaces for mobile terminals. As a contributor member of the MIPI Alliance and a world leader in test and measurement, Agilent is at the forefront in providing you		The Agilent U4998A protocol / audio / video analyzer and generator module enables you to test your devices to ensure they are compliant to the HDMI 1.4b as well as MHL (Mobile High-Definition Link) compliance test specification (CTS).
ice tool provides memory bus tri t.com/find/memory	iggering, debug and complia	Protocol Comp B4623B LPDDR	/3 Compliance and Analysis Tool (B4622A bliance requires B4621A)	(Gen2) through PCIe 8GT/s (Gen3). The Digital Test Console is the industry's most complete test solution for PCIe 3.0, with a PCIe			
				bus as well as slot interposer probes utilizing the ESP (Equalizing Snoop Probe) technology.	test interfaces.	dons for the Miri	
		B4602A Signal B4606A Advan B4607A Advan B4610A Data II	Extractor tool ced Customization Environment (Developer) ced Customization Environment (Runtime) mport Tool		eles tools, competition, etc.) http://		cos.agilent.com/portal/Coll.php?cld=-
li do ver li e	I for Xilinx and Altera FPGAs pro- icated to debug. Internal probe d pin mapping shortens measure v.agilent.com/find/fpga A, interposer and mid-bus probe ce tool provides memory bus tri c.com/find/memory rs – The ARM Cortex ETM/PTM you to view instructions and me identify what is happening and e system's behavior. http://www.	I for Xilinx and Altera FPGAs provides access to as many as 2 icated to debug. Internal probe points can be moved is second pin mapping shortens measurement setup time and elimit v.agilent.com/find/fpga A, interposer and mid-bus probes used in conjunction with the centre tool provides memory bus triggering, debug and complication.com/find/memory rs — The ARM Cortex ETM/PTM Decoder, used with an Agile you to view instructions and messages that are executing in identify what is happening and why by rapidly consolidating e system's behavior. http://www.agilent.com/find/logic-sw	Ifor Xilinx and Altera FPGAs provides access to as many as 256 internal icated to debug. Internal probe points can be moved is seconds dipin mapping shortens measurement setup time and eliminates v.agilent.com/find/fpga A, interposer and mid-bus probes used in conjunction with the DDR 2/3 ce tool provides memory bus triggering, debug and compliance ccom/find/memory From The ARM Cortex ETM/PTM Decoder, used with an Agilent you to view instructions and messages that are executing in your identify what is happening and why by rapidly consolidating data into e system's behavior. http://www.agilent.com/find/logic-sw-apps B4601C Serial B4601C Serial B4601C Serial B4601C Advan B4607A Advan B4610A Data I B4630A MATL. B4630A MATL. B4655A FPGA B4655A FPGA B4655A FPGA B4655A FPGA B4656A FPG	Logic Analyzer Application Solutions (http://www.agilent.com/find/logic-sw-apps) Ifor Xilinx and Altera FPGAs provides access to as many as 256 internal icated to debug. Internal probe points can be moved is seconds of pin mapping shortens measurement setup time and eliminates w. agilent.com/find/fpga A, interposer and mid-bus probes used in conjunction with the DDR 2/3 ce tool provides memory bus triggering, debug and compliance e.com/find/memory rs – The ARM Cortex ETM/PTM Decoder, used with an Agilent you to view instructions and messages that are executing in your identify what is happening and why by rapidly consolidating data into e system's behavior. http://www.agilent.com/find/logic-sw-apps B4601A Signal Extractor tool B4602A Advanced Customization Environment (Developer) B4607A Advanced Customization Environment (Runtime) B4630A MATLAB Connectivity Tool rial acquisition and stimulus capabilities required to independently B5501A-200, 89601A-300	E5390A: 34-ch (SE, Classic) E539RA: 17-ch (SE, half-size Classic) E538RA: 17-ch (DF, Classic) DDR3 BGA Probes W3631A: DDR3 x16 command and data W3633A: DDR3 x4/x8 command and data W3633A: DDR3 x4/x8 command and data w3633A: DDR3 x4/x8 command and data (options specify quantity: 001 = qty 1, 002 = qty Logic Analyzer Application Solutions (http://www.agilent.com/find/logic-sw-apps) Ifor Xilinx and Altera FPGAs provides access to as many as 256 internal icated to debug. Internal probe points can be moved is seconds to join mapping shortens measurement setup time and eliminates v.agilent.com/find/fpga B4655A FPGA Dynamic Probe for Altera E9524A Xilinx MicroBlaze trace core and inverse assembler E9524A Xilinx MicroBlaze trace core and inverse assembler PCI Express Agilent's U4300 Digital Test Console PCI Express protocol test solution supports all speeds of PCle, 2.5 GT/s (Gen1), 5.0 GT/s (Gen2), 15-0 GT/s (Gen2),	### ### ### ### ### ### ### ### ### ##	E5390A: 34-ch (SE, Classic) E5397A: 17-ch (DF, Classic) E5387A: 17-ch (DF, Classic) E538

I2C, CAN, SPI, RS-232 analysis probes with inverse

Refer to logic analyzer configuration tool for list of

http://www.ald.com/

supported devices

assemblers are available from Advanced Logical Design,

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debug and test new digital buses in RF designs. $\underline{\text{http://www.agilent.com/find/dvsa}}$

triggering and deep traces that cover a long period of system activity

http://www.agilent.com/find/pnbs

Low speed serial buses – analysis probes convert the low speed serial data into a parallel format enabling

Microprocessors and Microcontrollers – Monitor processor execution relative to the rest of the system.